Notice of References Cited	Application/Control No. 09/877,923	Applicant(s)/Patent Under Reexamination DEICHSEL ET AL.	
	Examiner James A. Menefee 9/16/03	Art Unit 2828	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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